Se	arch No	otes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/583,279	ISHIKAWA ET AL.	
Examiner	Art Unit	
Y. J. Han	2838	

	SEARCHED			
Class	Subclass	Date	Examiner	
363	65 71 131 149 152 163 164 165			
318	801 809	12/22/2007	JH	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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see sea	rch report	12/23/2007	JH

SEARCH NOTES (INCLUDING SEARCH STRATEGY))
		DATE	EXMR
PLUS		12/22/2007	JH
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